

<b>Notice of References Cited</b>	Application/Control No. 10/790,965		Applicant(s)/Patent Under Reexamination EDWARDS ET AL.	
	Examiner Dimple N. Bodawala		Art Unit 1722	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,842,194 A	10-1974	Clemens, Jon Kaufmann	369/126
*	B	US-4,517,668 A	05-1985	Takaoka et al.	369/111
*	C	US-4,845,000 A	07-1989	Takeoka et al.	430/14
*	D	US-4,947,384 A	08-1990	Suzuki et al.	369/279
*	E	US-5,586,109 A	12-1996	Inui et al.	369/277
*	F	US-6,382,955 B1	05-2002	Sandstrom, Chad R.	425/542
*	G	US-6,570,826 B2	05-2003	Hosokawa, Tetsuo	369/13.55
*	H	US-6,616,867 B2	09-2003	Kerfeld, Donald J.	264/1.33
*	I	US-6,829,212 B1	12-2004	Morita et al.	369/275.4
*	J	US-6,906,993 B2	06-2005	Wang et al.	369/275.3
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.